

**IN THE UNITED STATES PATENT AND TRADEMARK OFFICE**

In re U.S. Patent Application of )  
SHICHI et al. )  
Application Number: To Be Assigned )  
Filed: Concurrently Herewith )  
For: METHOD AND APPARATUS FOR SPECIMEN )  
FABRICATION )  
Attorney Docket No.: NITT.0161 )

Honorable Assistant Commissioner  
for Patents  
Washington, D.C. 20231

**INFORMATION DISCLOSURE STATEMENT**

Sir:

The above-referenced application is a Continuation of U.S. Application No. 09/985,537 filed on November 5, 2001. It includes the same disclosure as U.S. Patent Application Serial No. 09/985,537.

It is understood that the listed references will be considered in the examination of the application and that no separate copies of the same prior art are required to be provided since they were previously cited or transmitted in the foregoing prior application under 37 CFR Section 1.98(d). Form(s) PTO 1449 is enclosed listing references cited by the Examining Attorney and submitted by applicant in the prior applications.

This Information Disclosure Statement is submitted with the above-captioned U.S. Continuation application. Accordingly, no fee is due or payable at this time.

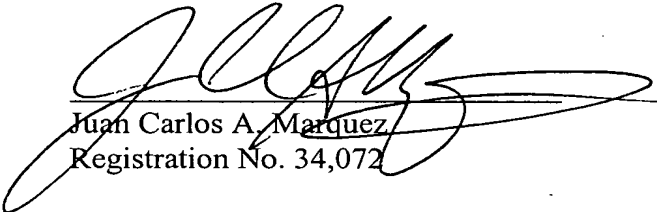
The Examiner is requested to acknowledge consideration of the information provided in this paper in accordance with prescribed procedures.

Please charge any additional fees or credit any overpayments in connection with this paper to Deposit Account No. 08-1480.

Respectfully submitted,

---

Stanley P. Fisher  
Registration Number 24,344



---

Juan Carlos A. Marquez  
Registration No. 34,072

**REED SMITH LLP**  
3110 Fairview Park Drive  
Suite 1400  
Falls Church, Virginia 22042  
(703) 641-4200  
**November 4, 2003**

Form PTO 1449  U.S. Department of Commerce Patent and Trademark Office.  Information Disclosure Statement by Applicant	ATTY. DOCKET NUMBER NITT.0161	SERIAL NUMBER To Be Assigned
	APPLICANT Shichi et al	
	FILING DATE Concurrently Herewith	GROUP

**U.S. Patent Documents**

Examiner Initial	Cited by Examiner in Parent	DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE
	X	6,039,000	3/21/2000	Libby et al.			2/11/98
	X	5,270,552	12/14/93	Ohnishi et al.			8/21/92
	X	5,986,264	11/16/99	Grunewald			4/22/96
	X	5,089,774	2/18/92	Nakano			12/24/90

**Foreign Patent Documents**

Examiner Initial	Filed In Parent	DOCUMENT NUMBER	FILING DATE	COUNTRY	CLASS	SUB-CLASS	TRANSLATION	
							YES	NO
	X	05-052721	8/22/91	Japan			Abstract	X
	X	WO99/05506	7/21/98	WO			Abstract	X
	X	03-166744	11/27/89	Japan			Abstract	X

**Other Documents (Including Author, Title, Date Pertinent Pages, Etc.)**

Filed in Parent		
X	L.A. Giannuzzi, J.I. Drown, S.R. Brown, R. B. Irwin, F.A. Stevie, "Focused Ion Beam Milling and Micromanipulation Lift-out for Site Specific Cross-Section TEM Specimen Preparation", Material Research Society Symposium Proceeding (1997), Vol. 480, pp. 19-27.	
X	L.R. Herlinger, S. Chevacharoenkul, D.C. Erwin, "TEM Sample Preparation Using a Focused Ion Beam and a Probe Manipulator", Proceedings of the 22 <sup>nd</sup> International Symposium for Testing and Failure Analysis, 18-22 November 1996, pp. 199-205	
X	"Election and Ion Beam Handbook", Third Edition, (Japan Society for the Promotion of Science, 132 commission, Nikkan Kogyo ShinbunSha), pp. 458-461	
EXAMINER		DATE CONSIDERED

*EXAMINER: Initial if citation is considered, whether or not citation is in conformance with MPEP 609; draw a line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant*